



Customer Information Notification

202106008I : S32R274 Data Sheet Updates from Rev. 5 to Rev. 6 & Reference Manual from Rev. 5 to Rev. 5.1

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Issue Date: Jul 23, 2021 **Effective date:** Sep 22, 2021

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Change Category

<input type="checkbox"/> Wafer Fab Process	<input type="checkbox"/> Assembly Process	<input type="checkbox"/> Product Marking	<input type="checkbox"/> Test Process	<input type="checkbox"/> Design
<input type="checkbox"/> Wafer Fab Materials	<input type="checkbox"/> Assembly Materials	<input type="checkbox"/> Mechanical Specification	<input type="checkbox"/> Test Equipment	<input type="checkbox"/> Errata
<input type="checkbox"/> Wafer Fab Location	<input type="checkbox"/> Assembly Location	<input type="checkbox"/> Packing/Shipping/Labeling	<input type="checkbox"/> Test Location	<input type="checkbox"/> Electrical spec./Test coverage
<input type="checkbox"/> Firmware <input checked="" type="checkbox"/> Other: Data Sheet and Reference Manual Update				

PCN Overview

Description

NXP Semiconductors announces a data sheet update for S32R274 from Rev. 5 to Rev. 6 and Reference Manual update from Rev. 5 to Rev. 5.1. The release notes included in the updated documents provide a detail description of the changes.

Data sheet changes:

1. In Table 26, removed the IMDSDA_MM_OFF, SNDRSDA_MM_OFF and SNRSDA_MM_OFF symbols.

The S32R274 Data Sheet Rev. 6 is attached to this notice and can be found at:
<https://www.nxp.com/docs/en/data-sheet/S32R274DS.pdf>



Reference Manual Changes:

1. Addendum S32R274 RM_Rev5.1 had been added to Reference Manual.

The S32R274 Reference Manual Rev 5.1 is attached to this notice and can be found at:
<https://www.nxp.com/webapp/Download?colCode=S32R274RM&location=null>

Corresponding ZVEI Delta Qualification Matrix ID: SEM-DS-02.

Reason

Remove agreed feature and provide additional technical clarification on related feature.

Identification of Affected Products

Product identification does not change

Anticipated Impact on Form, Fit, Function, Reliability or Quality

In ADC Control Register 1 (AFE_ADCCTRL1), changed the bit field value 1 of AFE_ADCCTRL1[MM_BYP] from "Mismatch shaper is bypassed" to "Reserved".

Data Sheet Revision

A new datasheet will be issued

Additional information

Additional documents: [view online](#)

Contact and Support

For all inquiries regarding the ePCN tool application or access issues, please contact NXP "Global Quality Support Team".

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For specific questions on this notice or the products affected please contact our specialist directly:

Name	NXP Technical Support
Position	NXP Technical Support
e-mail address	tech.support@nxp.com

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NXP Semiconductors
High Tech Campus, 5656 AG Eindhoven, The Netherlands

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